



Imaging Based Material Characterization of Electronics and Their Applications

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Message from the Guest Editor

This Special Issue aims to provide an excellent forum for scientists and engineers to share and exchange their latest contributions on the imaging base material characterizations of electronics and their applications. Within this context, original articles as well as insightful review articles are expected.

Keywords:

Deadline for manuscript
submissions:

closed (31 January 2022)

- Complex/functional materials,
- New imaging method development, Combination of multiple supplemental characterization,
- Eco-design, Recycling, Material Processing
- Process optimization/intensification
- Multiphase flows (e.g. liquid-gas flows, liquid-solid flows)
- Neutrons, X-rays
- *In-situ*/Operando measurement
- Tomography/radiography
- Magnetic resonance imaging
- Automated image analysis
- Electron microscope (e.g. SEM, TEM)

Welcome to contribute!





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Editor-in-Chief

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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